

Notice of References Cited	Application/Control No. 10/629,866	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Daniel Kim	Art Unit 2185	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0142660	10-2002	Abe, Takashi	439/631
*	B	US-6,144,576	11-2000	Leddige et al.	365/63
*	C	US-6,081,862	06-2000	Dixon et al.	710/307
*	D	US-2003/0043613	03-2003	Doblar et al.	365/63
*	E	US-2002/0041020	04-2002	Ono et al.	257/685
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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